

MS12N03

N-CHANNEL ENHANCEMENT MODE POWER MOSFET

BV _{DSS}	30V
R _{DS(ON)}	9mΩ
I _D	12A

Description

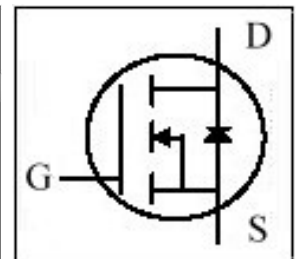
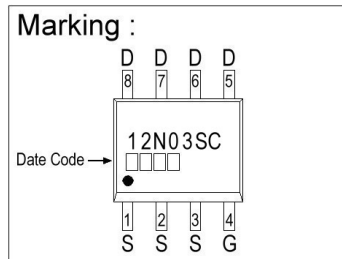
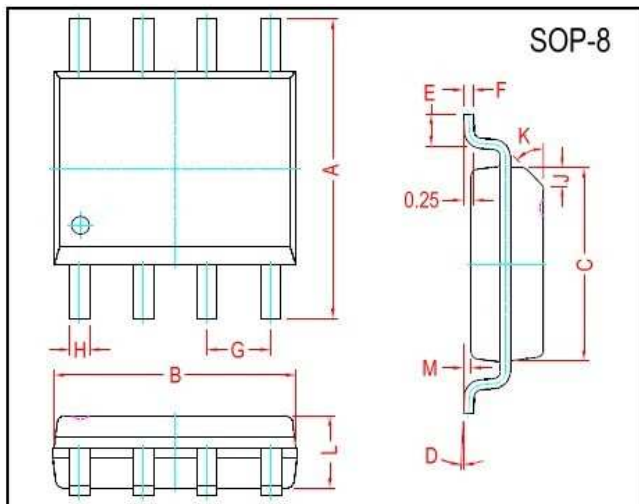
The MS12N03 is the highest performance trench N-ch MOSFETs with extreme high cell density, which provide excellent R_{DS(ON)} and gate charge for most of the synchronous buck converter applications.

The MS12N03 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full functional reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

Package Dimensions



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	5.80	6.20	M	0.10	0.25
B	4.80	5.00	H	0.35	0.51
C	3.80	4.00	L	1.35	1.75
D	0°	8°	J	0.40 REF.	
E	0.40	0.90	K	45° REF.	
F	0.19	0.26	G	1.27 TYP.	

Absolute Maximum Ratings

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V _{DS}	30	V
Gate-Source Voltage	V _{GS}	±20	V
Continuous Drain Current ¹	I _D @T _A =25°C	12	A
Continuous Drain Current ¹	I _D @T _A =70°C	8.2	A
Pulsed Drain Current ^{1,2}	I _{DM}	52	A
Single Pulse Avalanche Energy, L=0.1mH ³	E _{AS}	57.8	mJ
Single Pulse Avalanche Current, L=0.1mH ³	I _{AS}	34	A
Total Power Dissipation ⁴	P _D @T _A =25°C	1.5	W
Operating Junction and Storage Temperature Range	T _J , T _{STG}	-55 ~ +150	°C

Thermal Data

Parameter	Symbol	Max. Value	Unit
Thermal Resistance Junction-ambient ¹	R _{θJA}	85	°C/W
Thermal Resistance Junction-case ¹	R _{θJC}	50	°C/W

Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	BV_{DSS}	30	-	-	V	$V_{GS}=0, I_D=250\mu\text{A}$
Gate Threshold Voltage	$V_{GS(th)}$	1.0	-	2.5	V	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$
Forward Transconductance	g_{fs}	-	35	-	S	$V_{DS}=5\text{V}, I_D=10\text{A}$
Gate-Source Leakage Current	I_{GSS}	-	-	± 100	nA	$V_{GS} = \pm 20\text{V}$
Drain-Source Leakage Current ($T_J=25^\circ\text{C}$)	I_{DSS}	-	-	1	uA	$V_{DS}=24\text{V}, V_{GS}=0$
Drain-Source Leakage Current ($T_J=55^\circ\text{C}$)		-	-	5		$V_{DS}=24\text{V}, V_{GS}=0$
Static Drain-Source On-Resistance ²	$R_{DS(ON)}$	-	-	9	m Ω	$V_{GS}=10\text{V}, I_D=10\text{A}$
		-	-	13.5		$V_{GS}=4.5\text{V}, I_D=8\text{A}$
Total Gate Charge ²	Q_g	-	10.6	-	nC	$I_D=10\text{A}$ $V_{DS}=15\text{V}$ $V_{GS}=4.5\text{V}$
Gate-Source Charge	Q_{gs}	-	4.2	-		
Gate-Drain ("Miller") Charge	Q_{gd}	-	4.1	-		
Turn-on Delay Time ²	$T_{d(on)}$	-	5.8	-	ns	$V_{DD}=15\text{V}$ $I_D=10\text{A}$ $V_{GS}=10\text{V}$ $R_G=3.3\Omega$
Rise Time	T_r	-	61	-		
Turn-off Delay Time	$T_{d(off)}$	-	23.6	-		
Fall Time	T_f	-	7.6	-		
Input Capacitance	C_{iss}	-	1127	-	pF	$V_{GS}=0\text{V}$ $V_{DS}=15\text{V}$ $f=1.0\text{MHz}$
Output Capacitance	C_{oss}	-	194	-		
Reverse Transfer Capacitance	C_{rss}	-	77	-		
Gate Resistance	R_g	-	-	5	Ω	$f=1.0\text{MHz}$

Guaranteed Avalanche Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Single Pulse Avalanche Energy ⁵	EAS	20	-	-	mJ	$V_{DD}=25\text{V}, L=0.1\text{mH}, I_{AS}=20\text{A}$

Source-Drain Diode

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Diode Forward Voltage ²	V_{SD}	-	-	1	V	$I_S=1\text{A}, V_{GS}=0\text{V}, T_J=25^\circ\text{C}$
Continuous Source Current ^{1,6}	I_S	-	-	12	A	$V_G=V_D=0\text{V}, \text{Force Current}$
Pulsed Source Current ^{2,6}	I_{SM}	-	-	52	A	
Reverse Recovery Time	t_{rr}	-	14.1	-	ns	$I_F=10\text{A}, di/dt=100\text{A}/\mu\text{s}$
Reverse Recovery Charge	Q_{rr}	-	5.9	-	nC	$T_J=25^\circ\text{C}$

Notes: 1. The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.

2. The data tested by pulsed, pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.

3. The EAS data shows Max. rating. The test condition is $V_{DD}=25\text{V}, V_{GS}=10\text{V}, L=0.1\text{mH}, I_{AS}=34\text{A}$.

4. The power dissipation is limited by 150°C junction temperature.

5. The Min. value is 100% EAS tested guarantee.

6. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.

Typical Characteristics

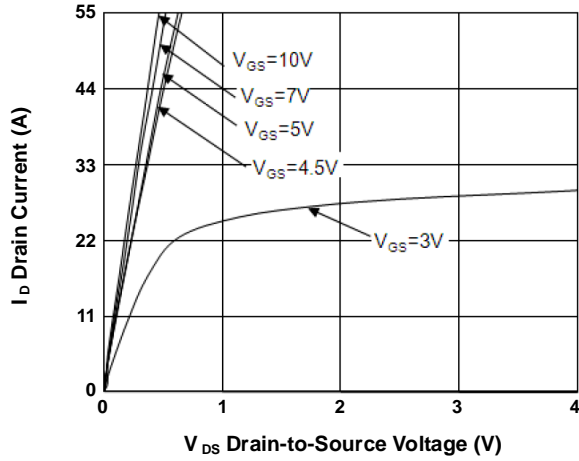


Fig.1 Typical Output Characteristics

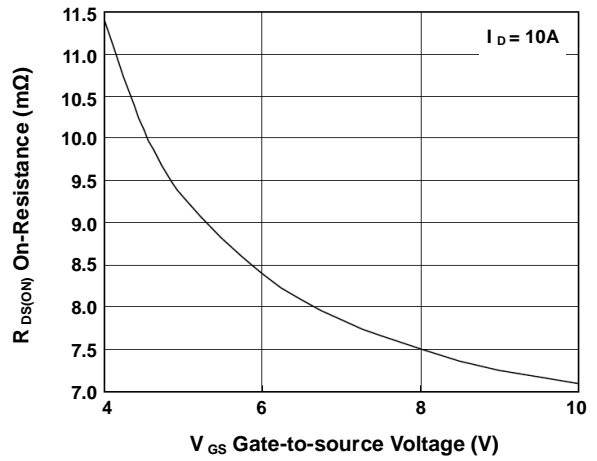


Fig.2 On-Resistance vs. G-S Voltage

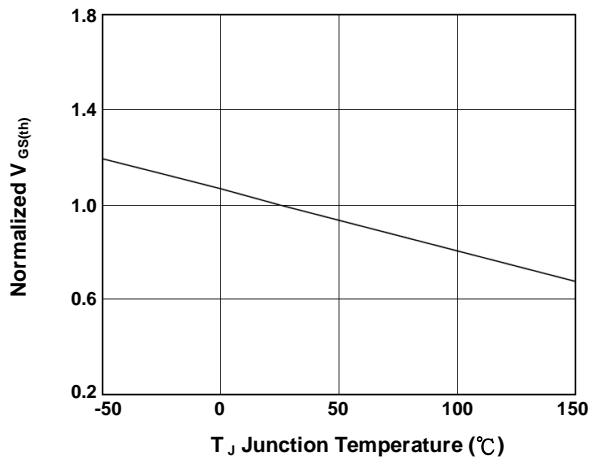


Fig.3 Normalized $V_{GS(th)}$ vs. T_J

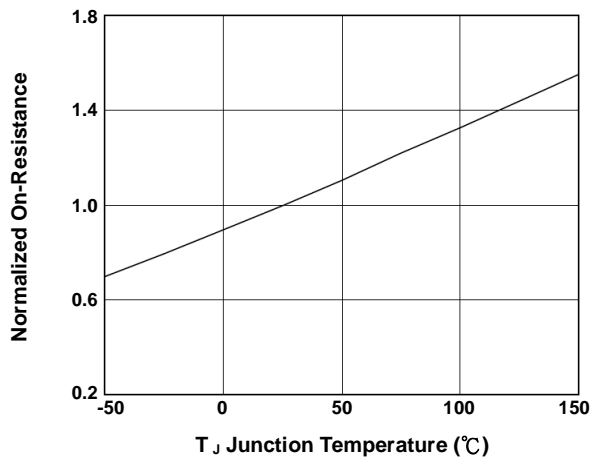


Fig.4 Normalized $R_{DS(on)}$ vs. T_J

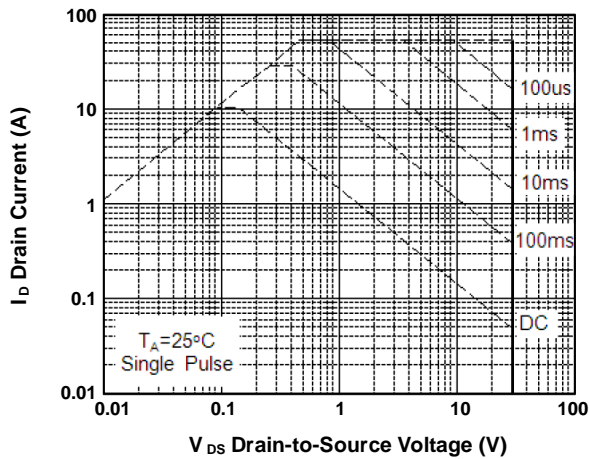


Fig.5 Safe Operating Area

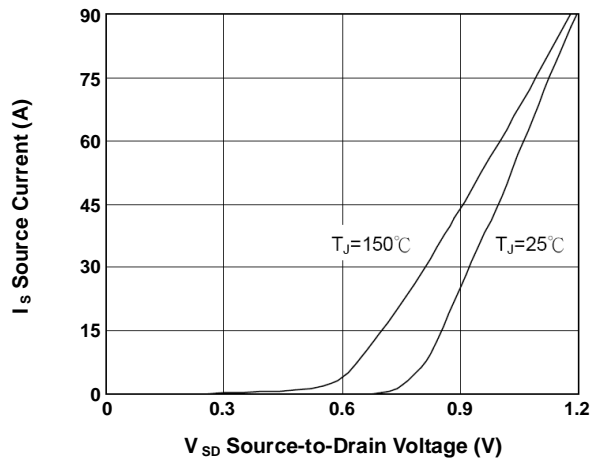


Fig.6 Forward Characteristics of Reverse

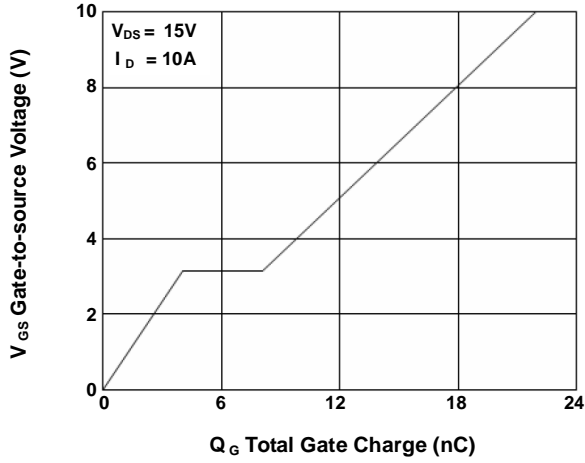


Fig.7 Gate Charge Characteristics

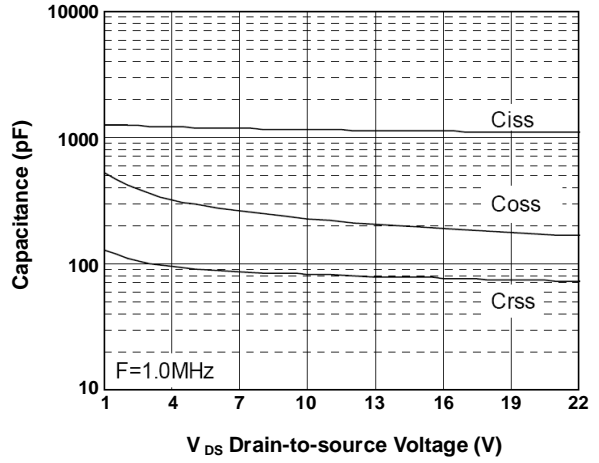


Fig.8 Capacitance Characteristics

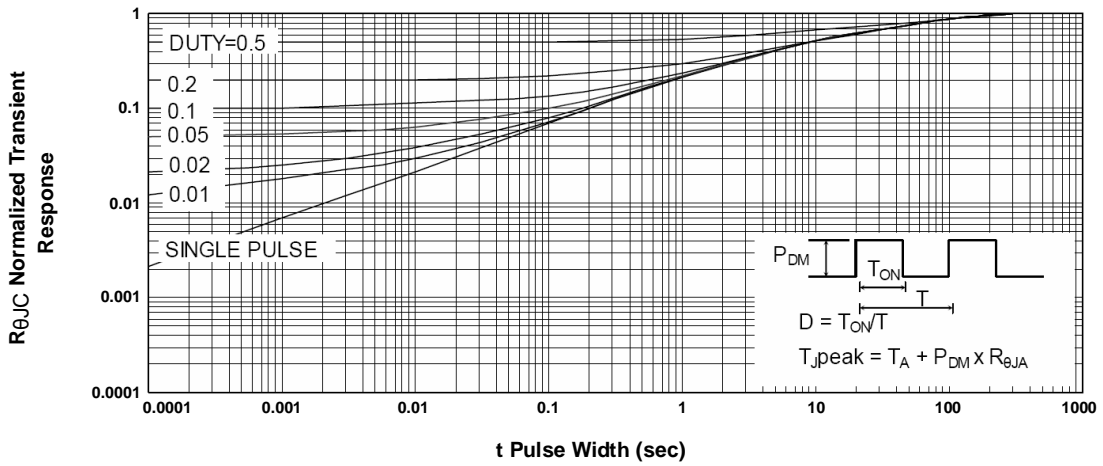


Fig.9 Normalized Maximum Transient Thermal Impedance

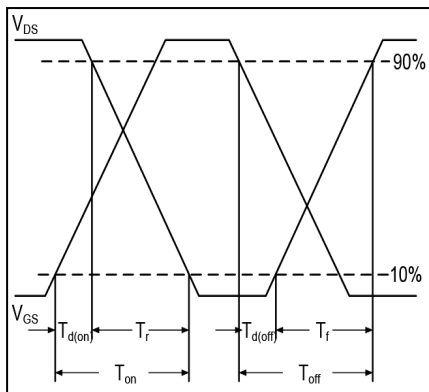


Fig.10 Switching Time Waveform

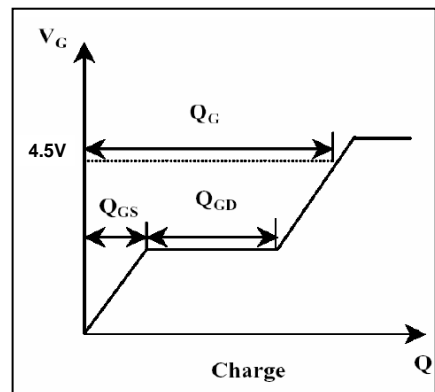


Fig.11 Gate Charge Waveform